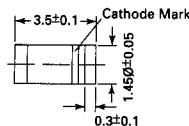


**Silicon Expitaxial Planar Diode**

fast switching diode in MiniMELF case especially suited for automatic surface mounting.

Identical electrically to standard JEDEC 1N4148



Glass case MiniMELF

These diodes are delivered taped.

Details see "Taping".

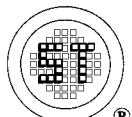
Weight approx. 0.05g

Dimensions in mm

**Absolute Maximum Ratings ( $T_a = 25^\circ\text{C}$ )**

	Symbol	Value	Unit
Reverse Voltage	$V_R$	75	V
Peak Reverse Voltage	$V_{RM}$	100	V
Rectified Current (Average) Half Wave Rectification with Resist. Load at $T_{amb} = 25^\circ\text{C}$ and $f \geq 50\text{ Hz}$	$I_0$	150 <sup>1)</sup>	mA
Surge Forward Current at $t < 1\text{ s}$ and $T_j = 25^\circ\text{C}$	$I_{FSM}$	500	mA
Power Dissipation at $T_{amb} = 25^\circ\text{C}$	$P_{tot}$	500 <sup>1)</sup>	mW
Junction Temperature	$T_j$	175	$^\circ\text{C}$
Storage Temperature Range	$T_s$	-65 to + 175	$^\circ\text{C}$

<sup>1)</sup> Valid provided that electrodes are kept at ambient temperature


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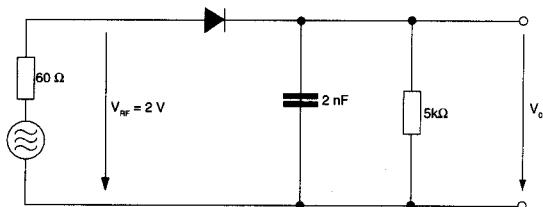
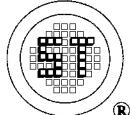
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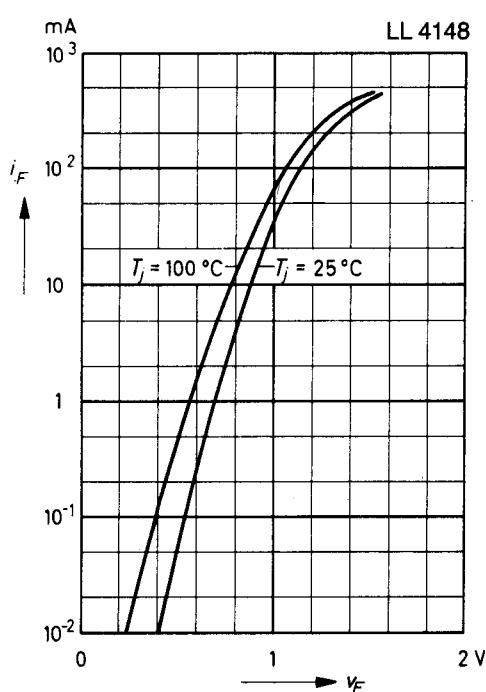
**Characteristics at  $T_j = 25^\circ\text{C}$** 

	Symbol	Min.	Typ.	Max.	Unit
Forward Voltage at $I_F = 10 \text{ mA}$	$V_F$	-	-	1	V
Leakage Current at $V_R = 20 \text{ V}$ at $V_R = 75 \text{ V}$ at $V_R = 20 \text{ V}, T_j = 150^\circ\text{C}$	$I_R$ $I_R$ $I_R$	- - -	- - -	25 5 50	nA $\mu\text{A}$ $\mu\text{A}$
Reverse Breakdown Voltage tested with 100 $\mu\text{A}$ Pulses	$V_{(BR)R}$	100	-	-	V
Capacitance at $V_F = V_R = 0$	$C_{\text{tot}}$	-	-	4	pF
Voltage Rise when Switching ON tested with 50 mA Forward Pulses $t_p = 0.1 \text{ s}$ , Rise Time < 30ns, $f_p = 5 \text{ to } 100 \text{ kHz}$	$V_{\text{fr}}$	-	-	2.5	V
Reverse Recovery Time from $I_F = 10 \text{ mA}$ to $I_R = 1 \text{ mA}$ , $V_R = 6 \text{ V}$ , $R_L = 100 \Omega$ ,	$t_{rr}$	-	-	4	ns
Thermal Resistance Junction to Ambient Air	$R_{\text{thA}}$	-	-	0.35 <sup>1)</sup>	K/mW
Rectification Efficiency at $f = 100 \text{ MHz}$ , $V_{RF} = 2 \text{ V}$	$\eta_V$	0.45	-	-	-

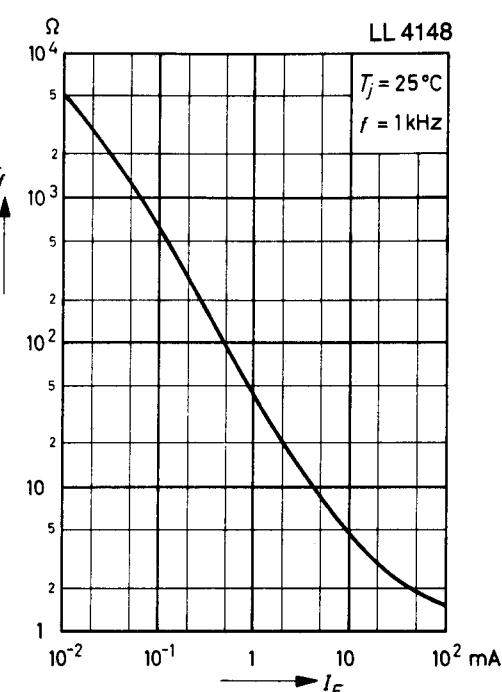
<sup>1)</sup> Valid provided that electrodes are kept at ambient temperature

**Rectification Efficiency Measurement Circuit****SEMTECH ELECTRONICS LTD.**( wholly owned subsidiary of **HONEY TECHNOLOGY LTD.** )

### Forward characteristics

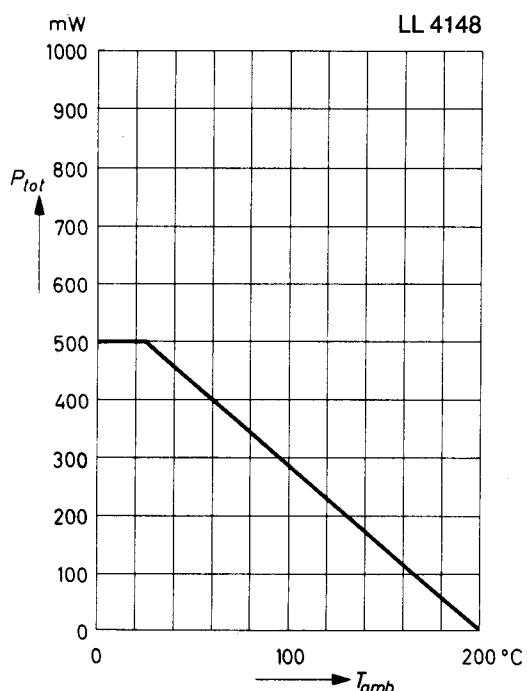


### Dynamic forward resistance versus forward current

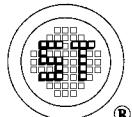
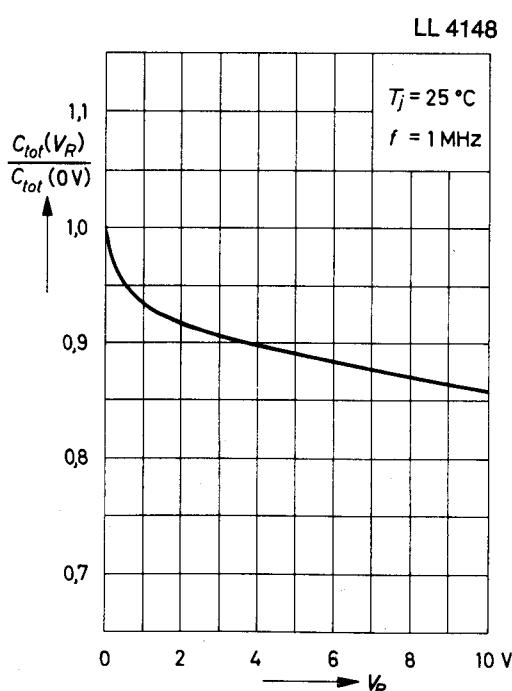


### Admissible power dissipation versus ambient temperature

Valid provided that electrodes are kept at ambient temperature



### Relative capacitance versus reverse voltage



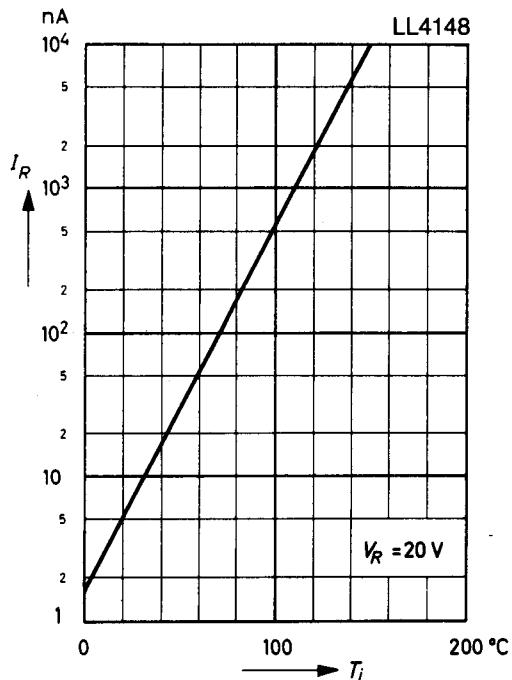
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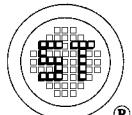
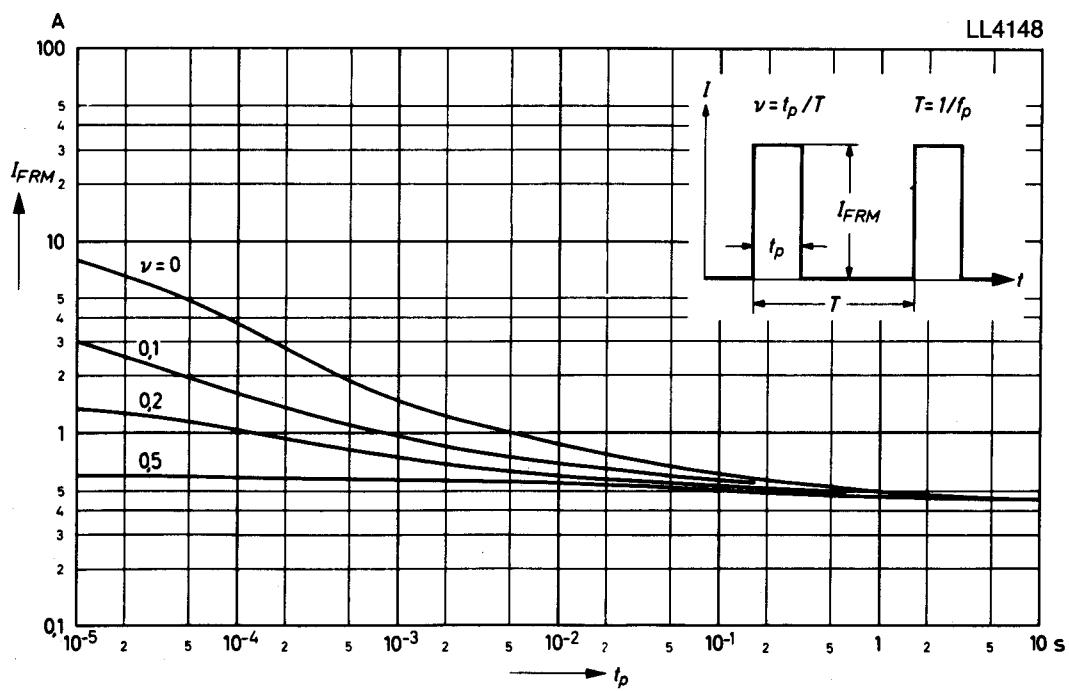
ISO 9002-94  
Certificate No. 080-5554

**Leakage current  
versus junction temperature**



**Admissible repetitive peak forward current versus pulse duration**

Valid provided that electrodes are kept at ambient temperature



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